**Conductive Nanoprobe for Probers**

Micro and nano-scale multi-probing techniques are used in semiconductor device R&D and production to probe sample surfaces, as when measuring the surface electrical characteristics for failure analysis. With the increasing intricacy of device structures in recent years, higher demands are placed on probe specifications such as increased sharpness and control of surface oxide films. Demand for such probes is also increasing in various other fields, including nanobiology.

To meet these needs, UNISOKU has developed contact inspection nanoprobes for a variety of applications.

### Small Tip Angle Produce Better Tip Shapes for Multi-probe Applications

Probe tips are shaped with a small tip angle so that probes can be placed close together at acute angles without touching one another.

### Capable of Soft Contact with Samples*1

Without an intervening surface oxide film, Nickel probes, PtIr-coated tungsten probes and Platiniridium probes make it possible to quickly achieve conductivity on contact, minimizing damage to samples and probes.

*1: Applies only to Nickel probes*2, PtIr-coated tungsten probes, and Platiniridium probes and not to Tungsten probes.

*2: Please refer to **Ni Probes Type: P-100Ni (S)**, in **High Performance STM Probes for Ni Probes** leaflet.

<table>
<thead>
<tr>
<th>PtIr Coating Tungsten Probes</th>
<th>Platiniridium Probes</th>
<th>Tungsten Probes</th>
</tr>
</thead>
<tbody>
<tr>
<td>Type: P-100W/PtIr (Low Contact Resistance)</td>
<td>Type: P-100PtIr (P) (Low Contact Resistance)</td>
<td>Type: P-100WP (Low Contact Resistance)</td>
</tr>
<tr>
<td>Shape: Cone</td>
<td>Shape: Cone</td>
<td>Shape: Cone</td>
</tr>
<tr>
<td>Wire Rod: Polycrystalline tungsten 0.25mm diameter</td>
<td>Wire Rod: Polycrystalline Platiniridium 0.5mm diameter</td>
<td>Wire Rod: Polycrystalline tungsten 0.25mm diameter</td>
</tr>
<tr>
<td><img src="image1.png" alt="SEM Image" /></td>
<td><img src="image2.png" alt="SEM Image" /></td>
<td><img src="image3.png" alt="SEM Image" /></td>
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</tbody>
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